I hereby certify that this correspondence is being deposited with the United States Postal Service as first class mail in an nv lope addressed to: Commissioner of Patents and Trademarks, Washington, D.C. 20231, on <u>August 4, 2003.</u> The applicant and/or attorney requests the date of deposit as the filing date. Depositor: Karen Cinq-Mars

ing-mas 141.03

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

ln re application of :

August 4, 2003

William C. Wille, et al.:

Group Art Unit:

Serial No. 10/604,533 :

Examiner:

Filed: 7/29/2003

International Business Machines Corporation

2070 Route 52

Hopewell Junction, NY 12533

TITLE:

Magnetic Random Access Memory and Method of Fabricating Thereof

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

Pursuant to the duty of disclosure set forth in 37 C.F.R. 1.56, and further pursuant to the provisions of 37 C.F.R. 1.97 and 1.98, applicants hereby respectfully submit copies of the prior patents and publications as listed on Form PTO-1449, attached hereto.

In citing these documents, no representation is made nor intended as to the pertinency or non-pertinency of the art, that better art than that listed is not available, or that other art is not applicable.

No fee is believed to be due for this submission. If any fees are required, however, the Commissioner is hereby authorized to charge such fees to Deposit Account No. 09-0458.

Respectfully submitted, William C. Wille, et al.

Margaret A. Pepper, Attorney

Registration No. 45,008

Telephone No. 845-894-4713

2		MATION DISCLOSURE (Use several sheet) if necessary	E CITATION	FIS92002013 Applicant(s)	NUETZEL ET AL.		NYA		
	67/			NYA		NYA			
	- 1	TRADEIL CHE		S. PATENT DOCUMENTS		·			
EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE		
·									
	-					 			
	_				,				
1	1		FG	DREIGN PATENT DOCUMENTS					
	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation		
						5020225	YES NO		
		· · · · · · · · · · · · · · · · · · ·							
	_								
	<u>, L</u>		I I	THER DOCUMENTS (Including	g Author, Title, Da	ta Partinant Pac	ran Eta l		
L. G. Svendsen, T. Osaka, I. Koiwa, and H. Sav Rutherford Backscattering Spectrometry; J. Vol. 130 No. 11, November 1983, pages			Sawai; "Chemically Deposited J. Electrochem. Soc.: SO						
,	2	K. K. H. Wong, S. Kaja, P. W. DeHaven; "Metallization By Plating for High-Performance Multichip Modules," IBM Research Development, Vol. 42, No. 5, September 1998; pages 587 - 596.							
KAMINER				DATE CONSIDERED	DATE CONSIDERED				
KAMINER: t considere	: Initial i	f citation considered, whether or de copy of this form with next co	r not citation is in conformunication to appli	ormance with MPEP Section 609; cant.	Draw line throug	h citation if not i	n conformance and		

			Docket Number (Optional)	Application Number				
INI	en M	ATION DISCLOSURE CITATION	FIS920020132US1 Applicant(s)	NYA				
ALVA		(Use several shows if necessary)	NUETZEL ET AL.	T				
	AU 22	UG 0 6 2003 w	Filing Date NYA	Group Art Unit NYA				
*EXAMINER INITIAL	(B)	OFFICE DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)						
MILIAL	-	PAGE AND ASARO, J. V. DiLorenzo, and H. Fukui; "Improved Performance of GaAs Microwave Field-Effect Transistors with Low Inductance Via Connections Through the Substrate;" IEEE Transactions on Electron Devices, Vol. ED-25, No. 10, October						
	3	1978; pages 1218 - 1221.	.e;" IEEE 1 ransactions on electron 1	Jevices, Vol. ED-25, No. 10, October				
		T. Ishikawa, K. Okaniwa, M. Komaru, K. Kosaki, and Y. Mitsui; "A High-Power GaAs FET Having Buriled Plated Heat Sink for High-Performance MMIC's" IEEE Transactions on Electron Devices, Vol. 41, No. 1; January 1994; pages 3 - 9						
	4	for High-Performance MMIC'S" IEEE 1 ransacuo	ns on Electron Devices, Vol. 41, No.	1; January 1994; pages 3 - 9				
	-							
				1,000				
ļ								
1								
1								
-								
!	1							
<u> </u>	<u> </u>							
	, 							
	1							
EXAMINER			T					
EXAMINER		V	DATE CONSIDERED					
. Total Park I Park								
*EXAMINER: II not considered.	iitial 11 c Include (citation considered, whether or not citation is in conformatic copy of this form with next communication to applicant.	nce with MPEP Section 609; Draw line the	hrough citation if not in conformance and				